

<b>Notice of References Cited</b>	Application/Control No. 09/649,788	Applicant(s)/Patent Under Reexamination WONG ET AL.	
	Examiner Son P Huynh	Art Unit 2611	Page 1 of 1

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	C	US-6,266,814 B1 ✓	07-2001	Lemmons et al.	725/44
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**NON-PATENT DOCUMENTS**

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